

WATER PERMEATION AND ELECTRICAL PROPERTIES OF POTTANTS, BACKINGS, AND POTTANT/BACKING COMPOSITES

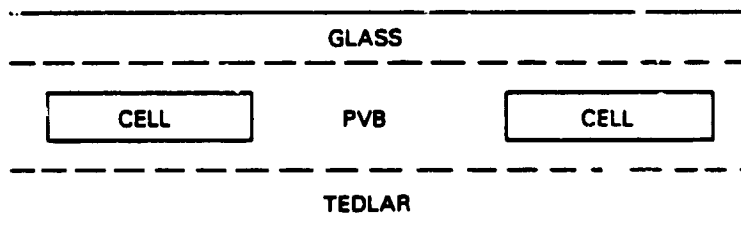
WILKES COLLEGE

J. Orehotsky

Laminates

DISCRETE INTERFACE MODEL	MIXING (ALLOY PHASES) MODEL
PVB	PVB
TEDLAR	PVB-TEDLAR ALLOY PHASES
	TFOLAR

FOR PATH OF LEAST RESISTANCE IN



Electrical Properties

- Pottants (PVB, EMA, EVA)
- Backing (Tedlar, Mylar)
- Composites (PVB/T, EMA/T, EVA/T)

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RELIABILITY PHYSICS

Object

To Examine Interfacial Effects
by
Evaluating

- DC Dielectric Constant (K)
- AC Dielectric Constant (K)
- Leakage Resistance (R)

of

Pottants (PVB, EMA, EVA)

Backing (Tedlar, Mylar)

Composites (PVB/T, EMA/T, EVA/T)

Theory

Discrete Interface Model

$$K_{p/b} = \frac{K_p K_b [t_p + t_b]}{K_p t_b + K_b t_p}$$

$$R_{p/b} = \frac{\rho_p t_p + \rho_b t_b}{A}$$

RELIABILITY PHYSICS

DC Dielectric Constant by Charge Measurements Before and After Dipole Alignment

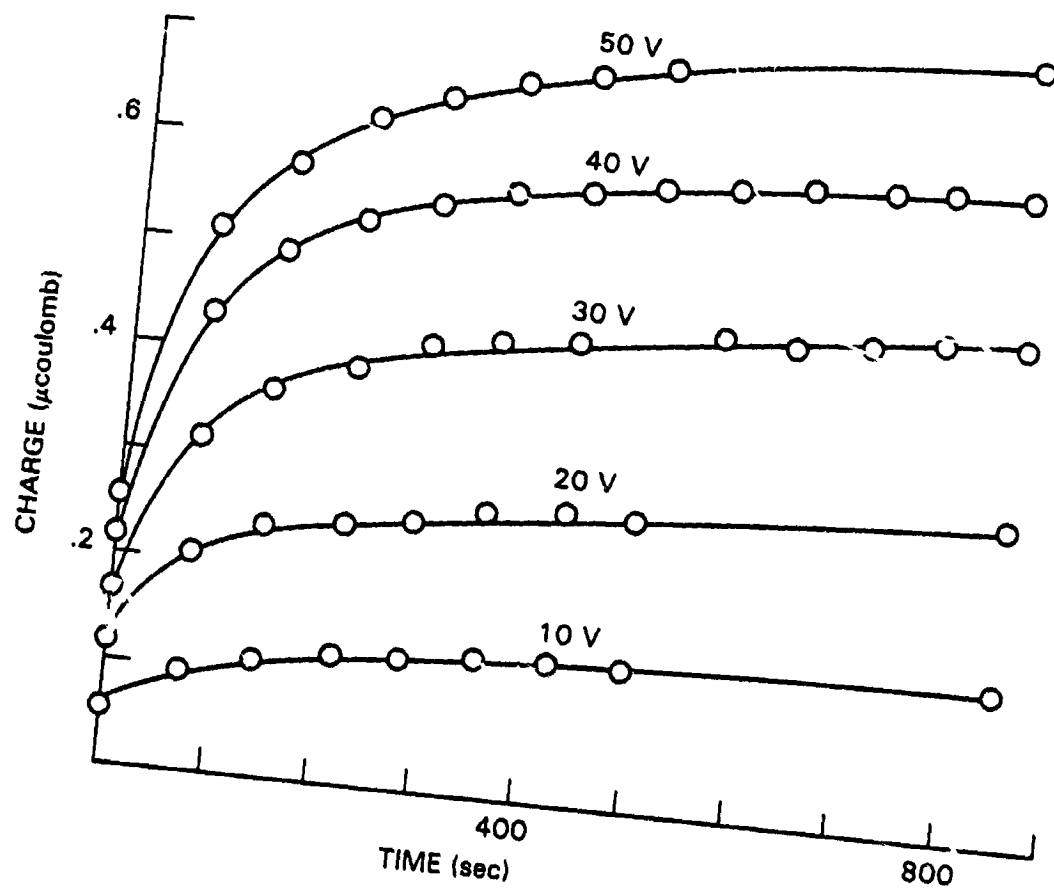
Before:

$$K_i = \frac{[dQ_i/dV_A]t}{\epsilon_0 A}$$

After:

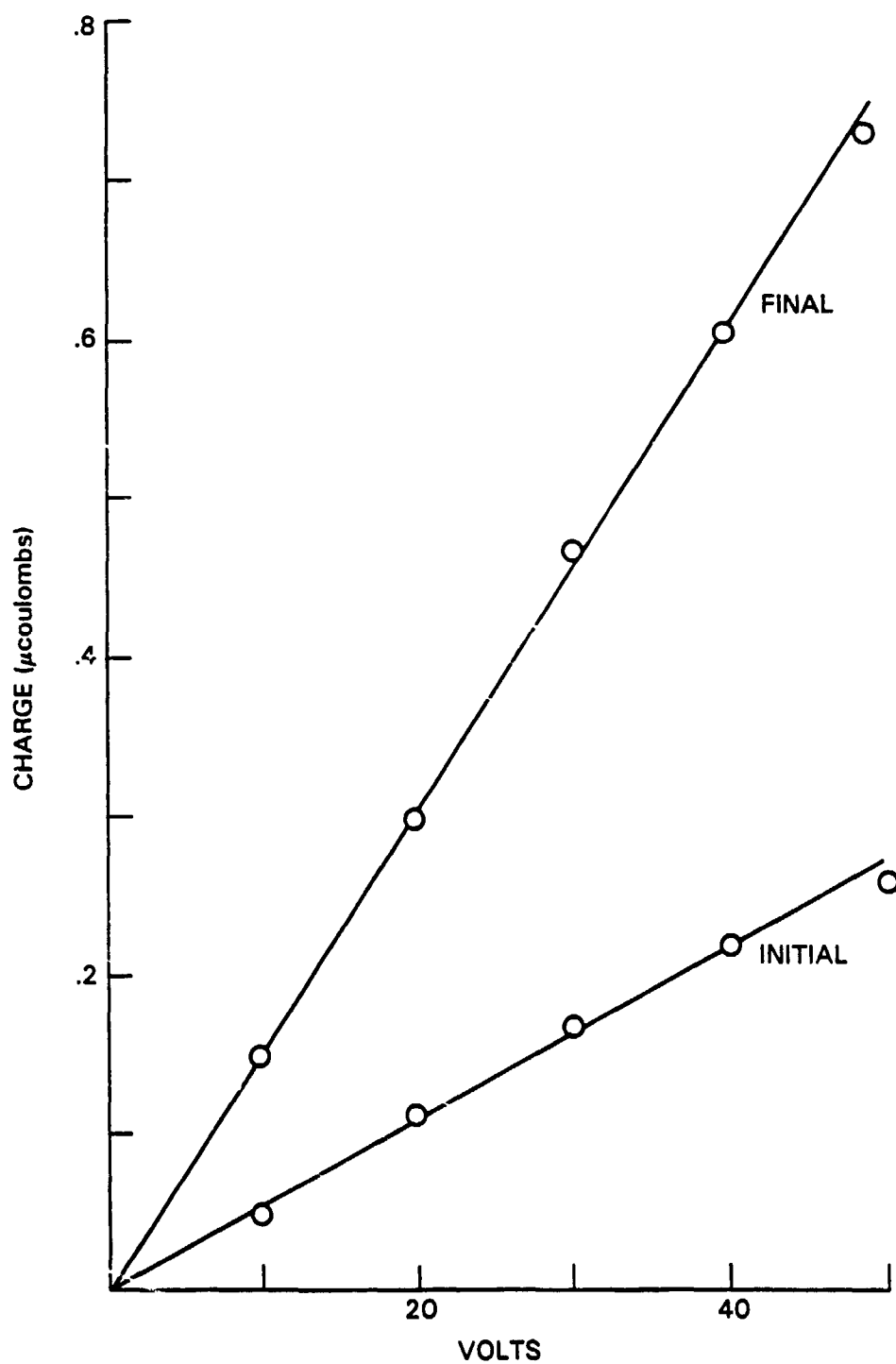
$$K_f = \frac{[dQ_f/dV_A]t}{\epsilon_0 A}$$

TEDLAR



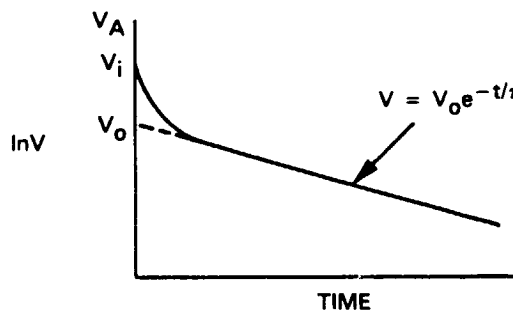
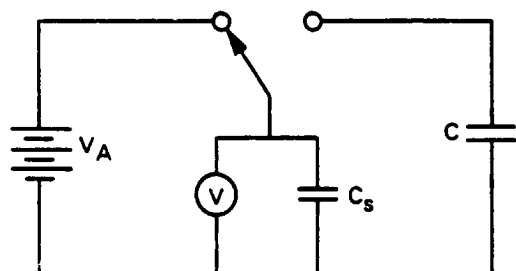
RELIABILITY PHYSICS

TEDLAR



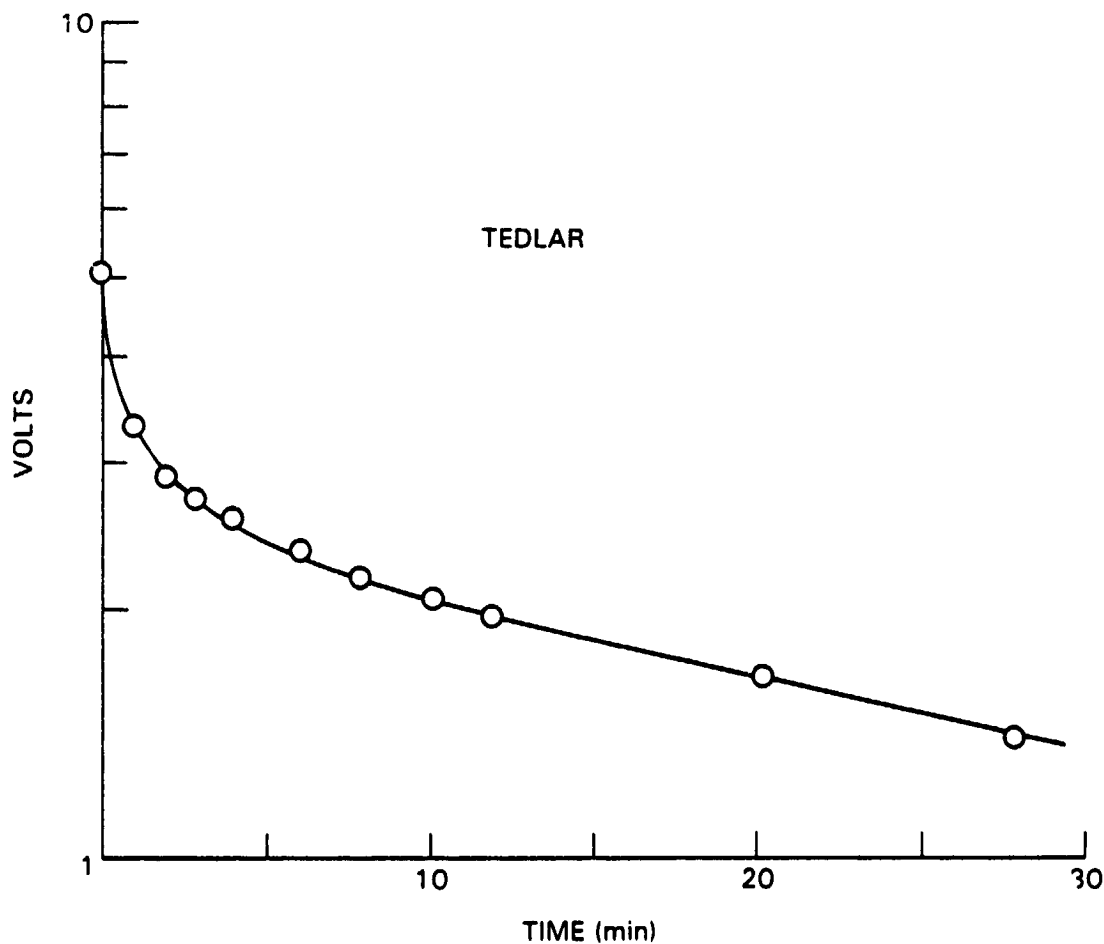
RELIABILITY PHYSICS

DC Dielectric Constant by Voltage Measurements Using Charge Transfer from Standard Capacitor (C_s)

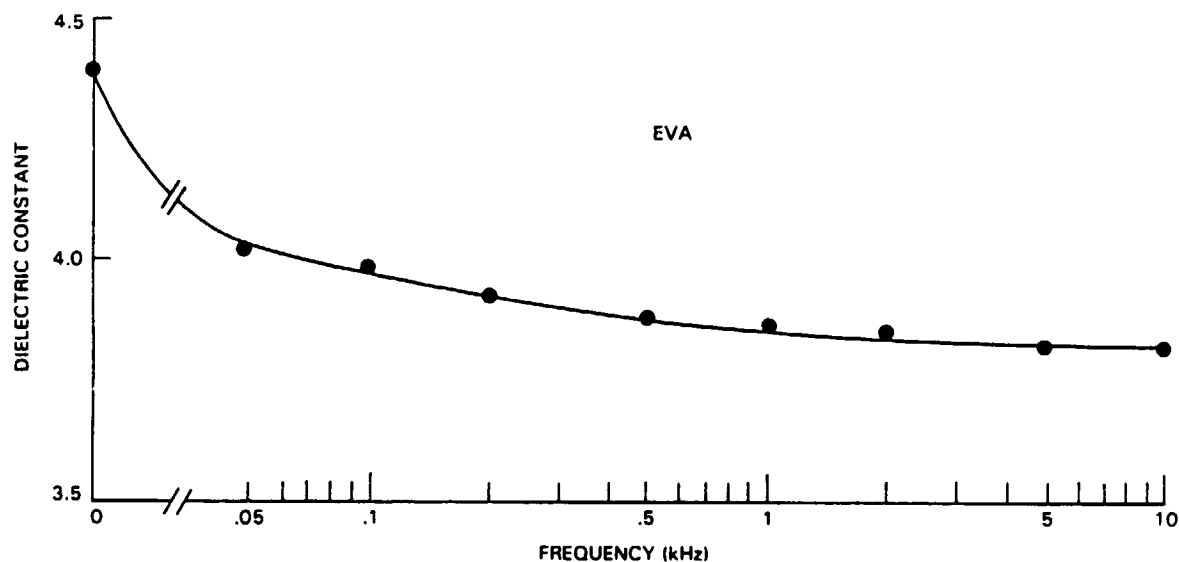


$$K_i = \frac{C_s t}{\epsilon_0 A} \left[\frac{V_A - V_i}{V_i} \right]$$

$$K_f = \frac{\tau}{\epsilon_0 A} \left[\frac{\tau}{R} \cdot C_s \right]$$



RELIABILITY PHYSICS



Results

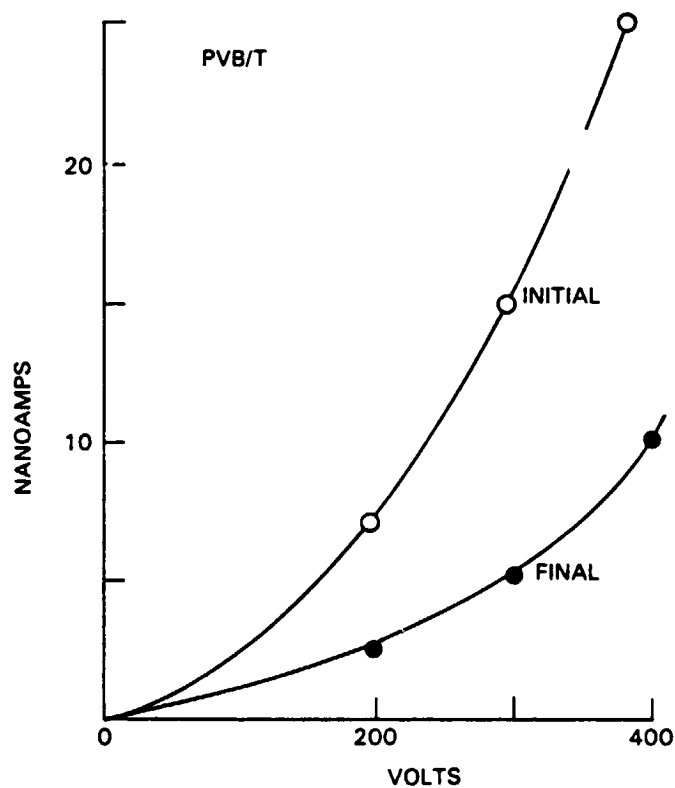
Dielectric Constant

	DC						AC	
	Before			After			1 kHz	Calc.
	<u>Q</u>	<u>V</u>	<u>Calc.</u>	<u>Q</u>	<u>V</u>	<u>Calc.</u>		
PVB	—	6.0		—	8.0		8.7	
EMA	4.3	4.7		4.3	7.1		3.1	
EVA	5.2	4.3		9.4	10.0		3.9	
Tedlar	4.5	4.3		12.7	12.0		3.7	
Mylar	1.3	1.4		—	—		—	
PV3/T	9.1	8.2	5.7	—	—	8.4	4.8	7.3
EMA/T	4.0	3.2	4.3	—	4.7	4.7	3.1	3.1
EVA/T	4.4	4.7	4.7	—	—	9.9	3.7	3.9

RELIABILITY PHYSICS

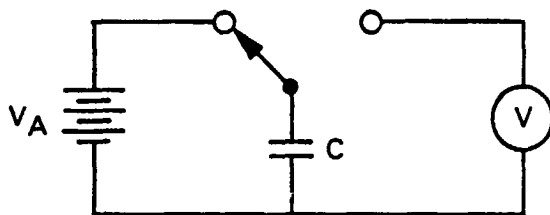
Leakage Resistance by Current-Voltage Measurements and Ohm's Law

$$R = dV_A/JI$$



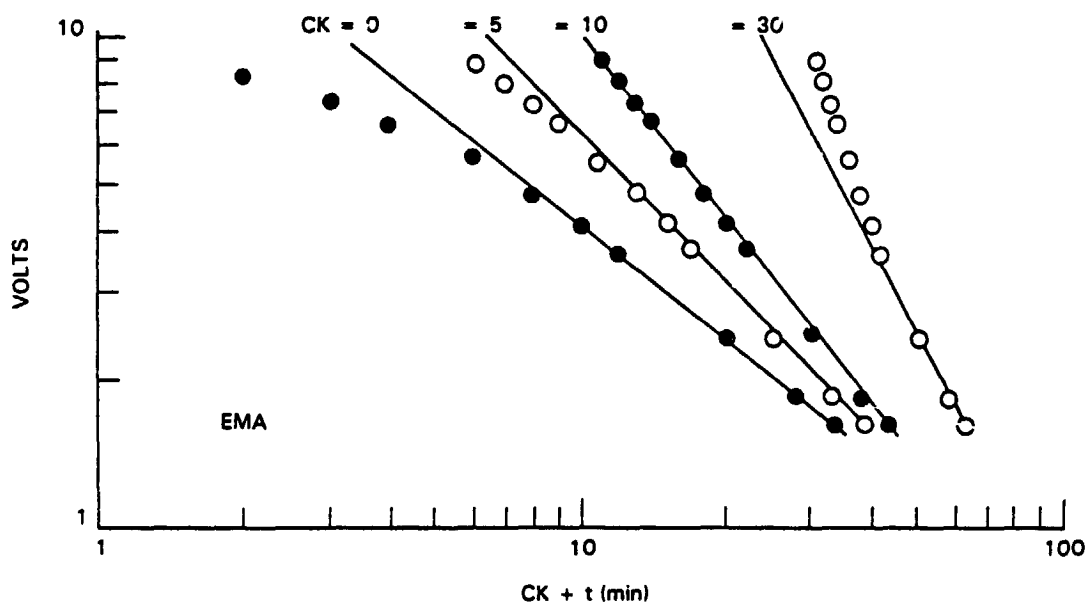
RELIABILITY PHYSICS

Leakage Resistance by Voltage Decay of a Capacitor



THEORY:

$$V = V_0 CK^{K/R} [CK + t]^{-K/R}$$



Results: Leakage Resistance (Ω)

	<u>Ohm's Law</u>	<u>Voltage Decay</u>	<u>Calc.</u>
PVB	1.0(10 ⁷)	0.4(10 ⁷)	
EMA	1.0(10 ¹²)	0.9(10 ¹²)	
EVA	0.4(10 ¹¹)	4.6(10 ¹¹)	
Tedlar	3.5(10 ¹¹)	2.0(10 ¹¹)	
Mylar	—	1.4(10 ¹³)	
PVB/T	0.2(10 ¹²)	6.8(10 ⁹)	3.4(10 ¹²)
EMA/T	0.3(10 ¹³)	2.3(10 ¹³)	0.1(10 ¹³)
EVA/T	0.3(10 ¹²)	0.8(10 ¹²)	3.4(10 ¹²)

RELIABILITY PHYSICS

Results: Leakage Resistivities ($\Omega\cdot m$)

PVB	$3(10^7)$
EVA	$5(10^{11})$
EMA	$1(10^{13})$
Tedlar	$4(10^{14})$
Mylar	$2(10^{15})$

Results: Are They Consistent with Discrete Interface Model?

Test	Composite Material		
	<u>EVA/T</u>	<u>EMA/T</u>	<u>PVB/T</u>
DC diel.	Yes	Yes	No
AC diel.	Yes	Yes	No
Resis.	No	Yes	No

Summary

- EMA/T Obeys Discrete Interface Model
- PVB/T Does Not Obey Discrete Interface Model
- Order of Increasing Leakage is Mylar, Tedlar, EMA, EVA, PVB
- Charged Capacitor-Voltage Decay Kinetics Obey Theoretically Predicted Relationship:

$$V = V_0 CK^{K/R} [CK + t]^{-K/R}$$

Water Permeation

- Pottants (PVB, EMA, EVA)
- Backing (Tedlar, Mylar)
- Composites (PVB/T, EMA/T, EVA/T)

Object

Theoretically and Experimentally Evaluate

- Temperature Dependence of
J (water flux)
and
P (water permeability)
in
Pottants (p) and Backing (b)
- $P_{p/b}$ of p/b Composite in terms of
 P_p and P_b

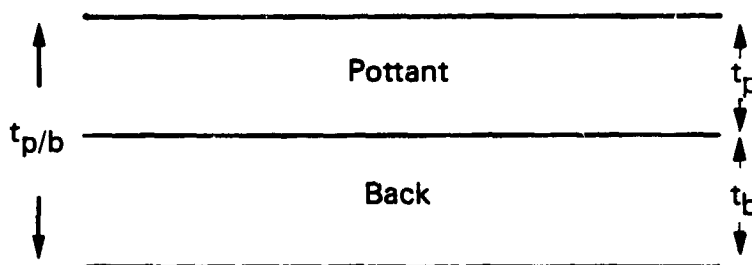
Theory: Condensation — Self Diffusion — Evaporation Model for Pottants and Backing

- $P_T = P_0 \exp(-Q_P/RT)$
 $Q_P = 4.6 \text{ Kcal/mole}$ (water self-diffusion
activation energy)
- $J T^{6.5} = J_0 \exp(-Q_J/RT)$
 $Q_J = 4.6 + 9.8 = 14.4 \text{ Kcal/mole}$
(water self-diffusion + water heat of vaporization)
 $J_0 \sim S$ (water solubility parameter)

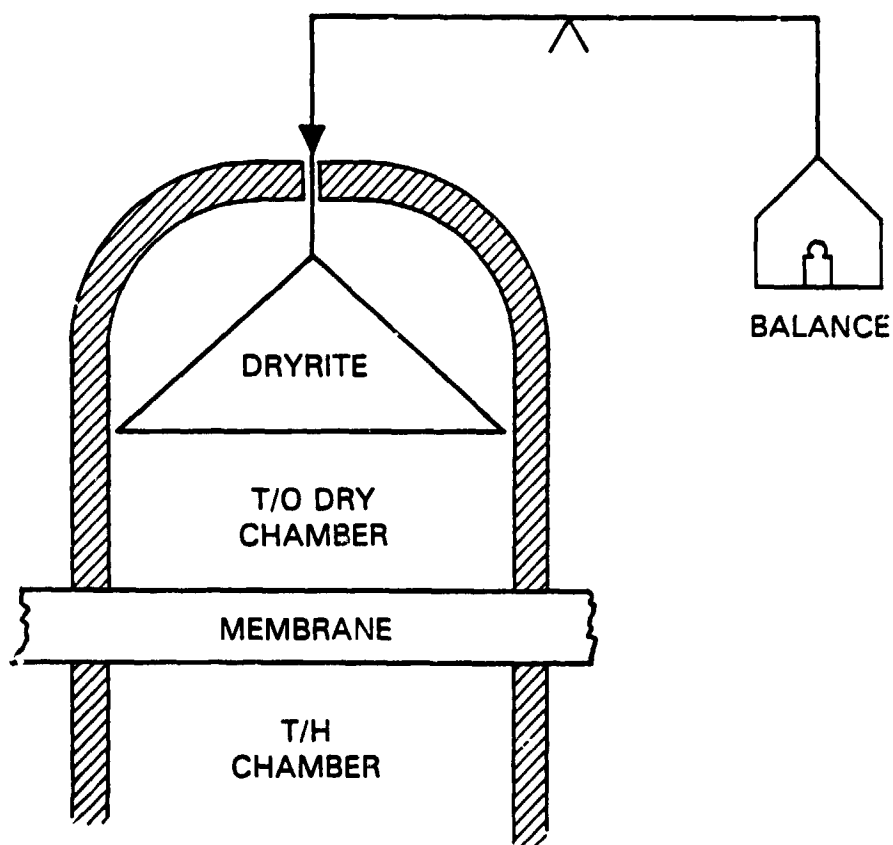
RELIABILITY PHYSICS

Theory: Discrete Interface Model for Composites (p/b)

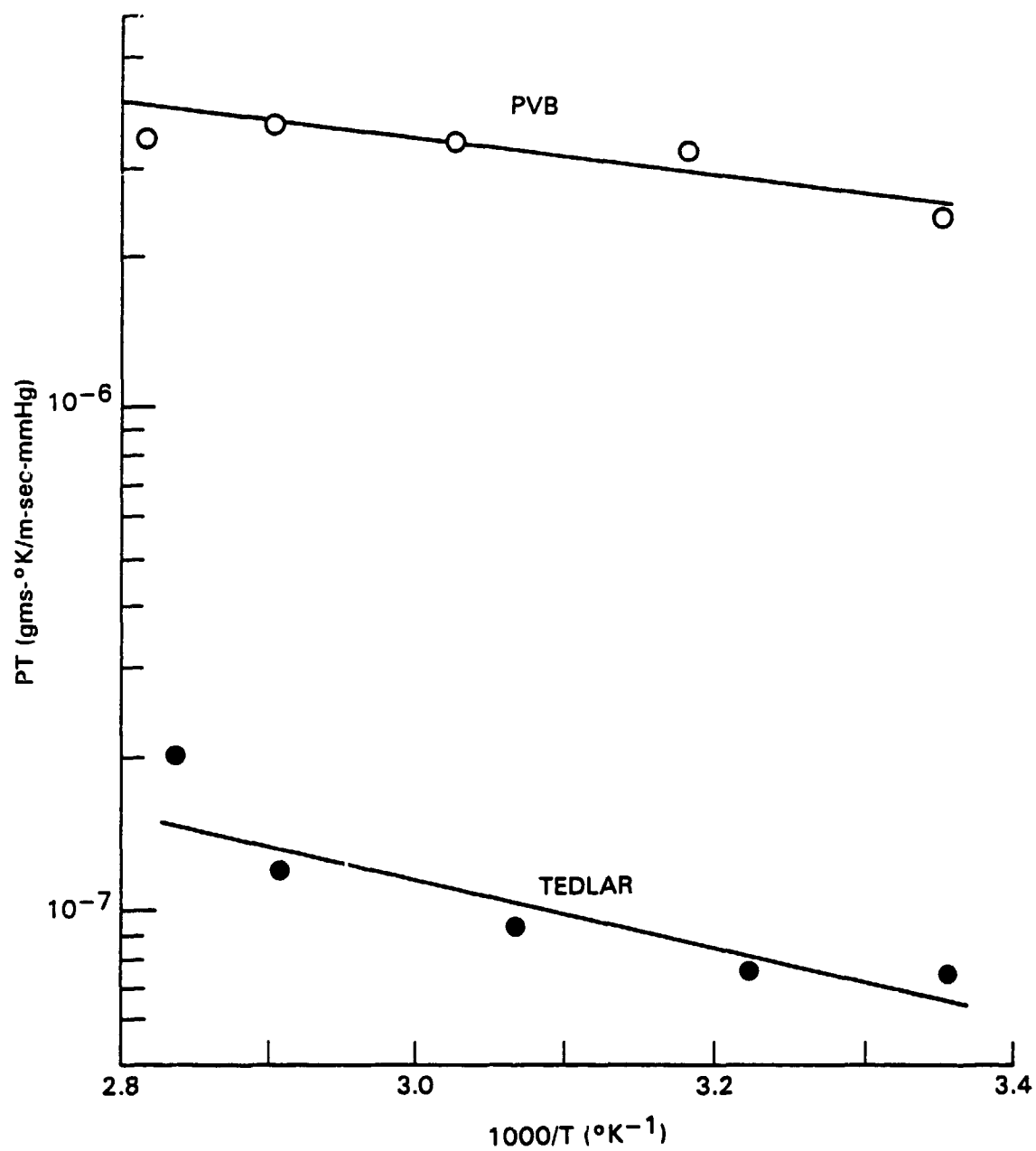
$$P_{p/b} = \frac{t_{p/b} P_p P_b}{P_p t_b + P_b t_p}$$



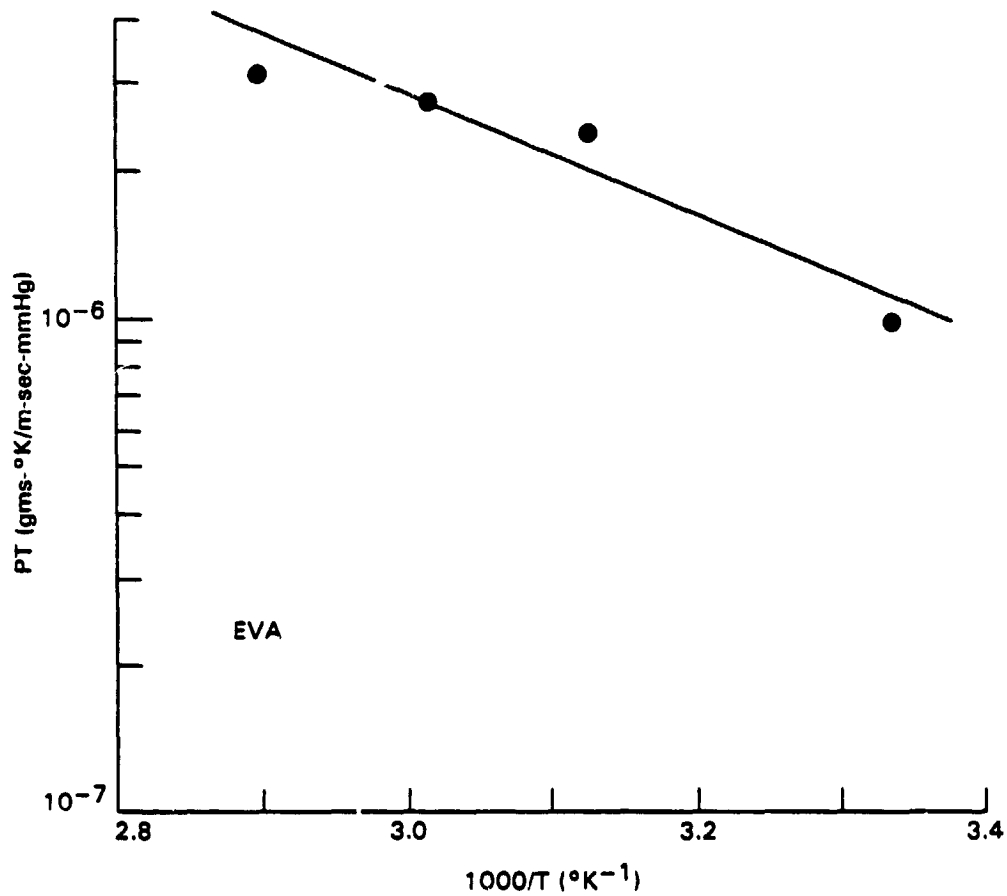
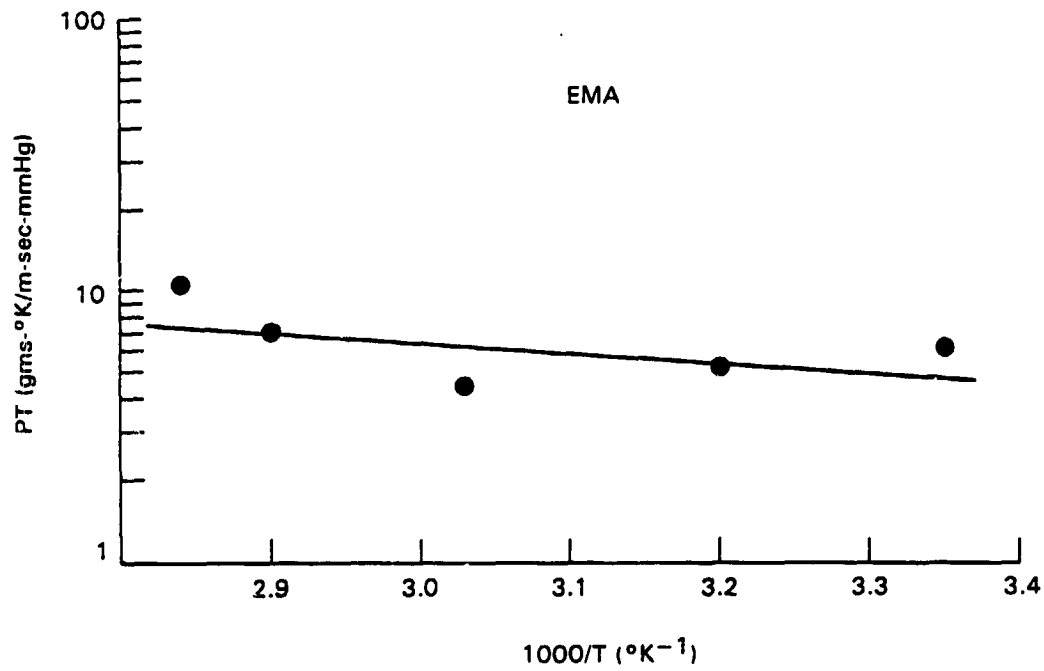
Experimental Arrangement



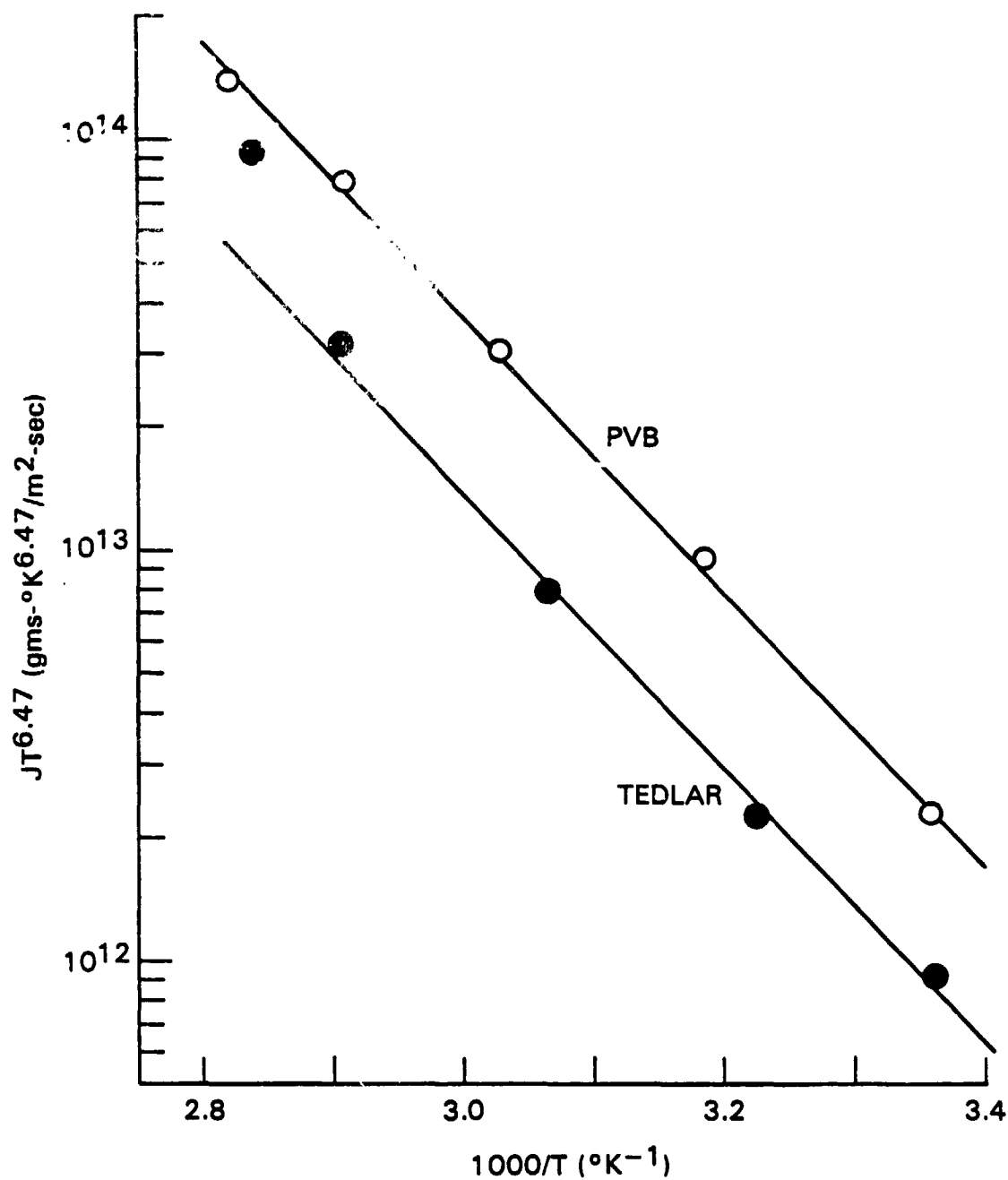
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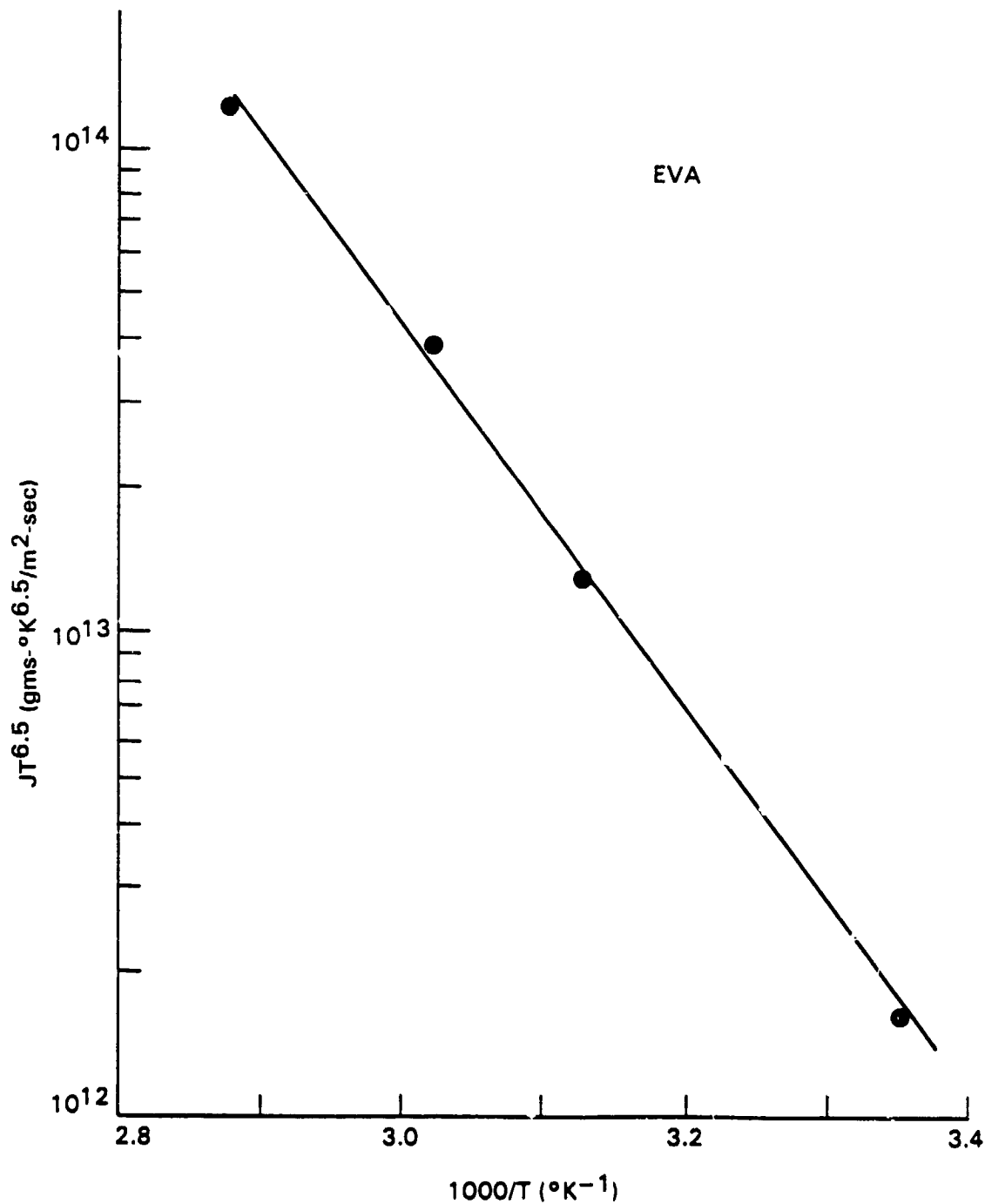
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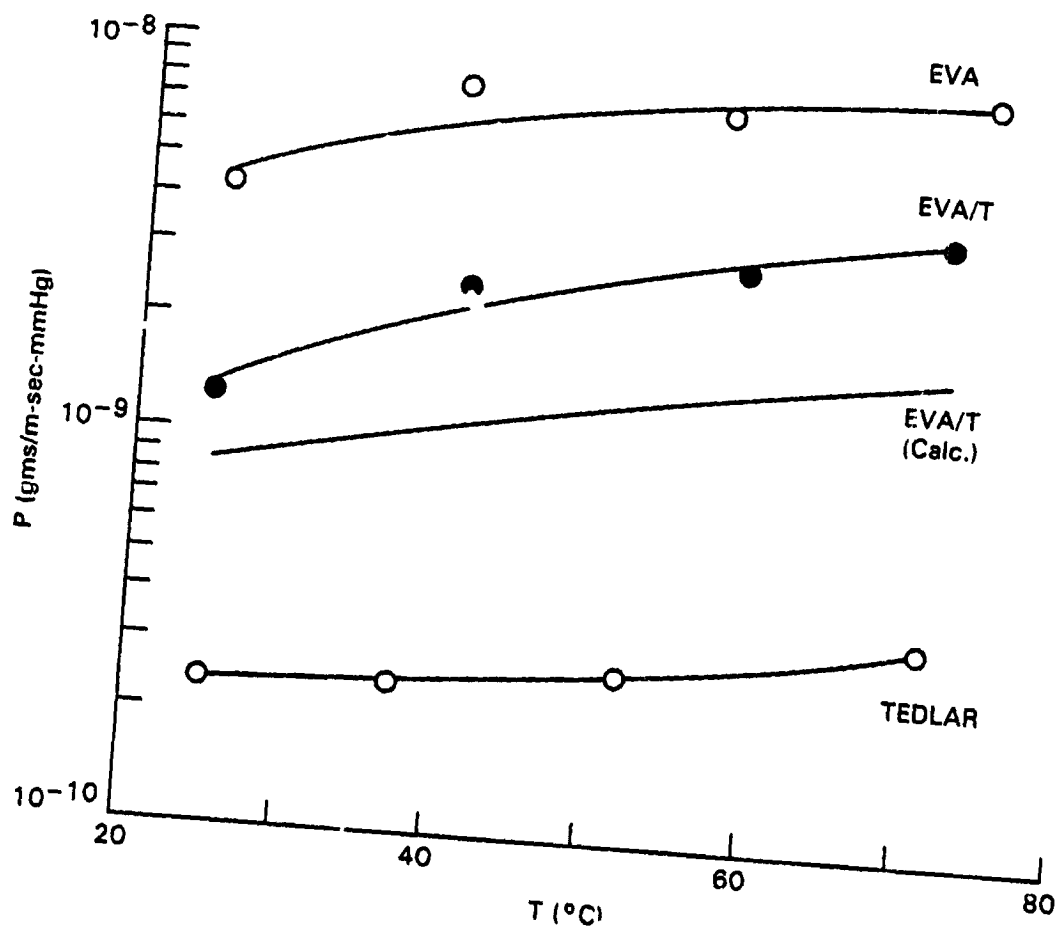
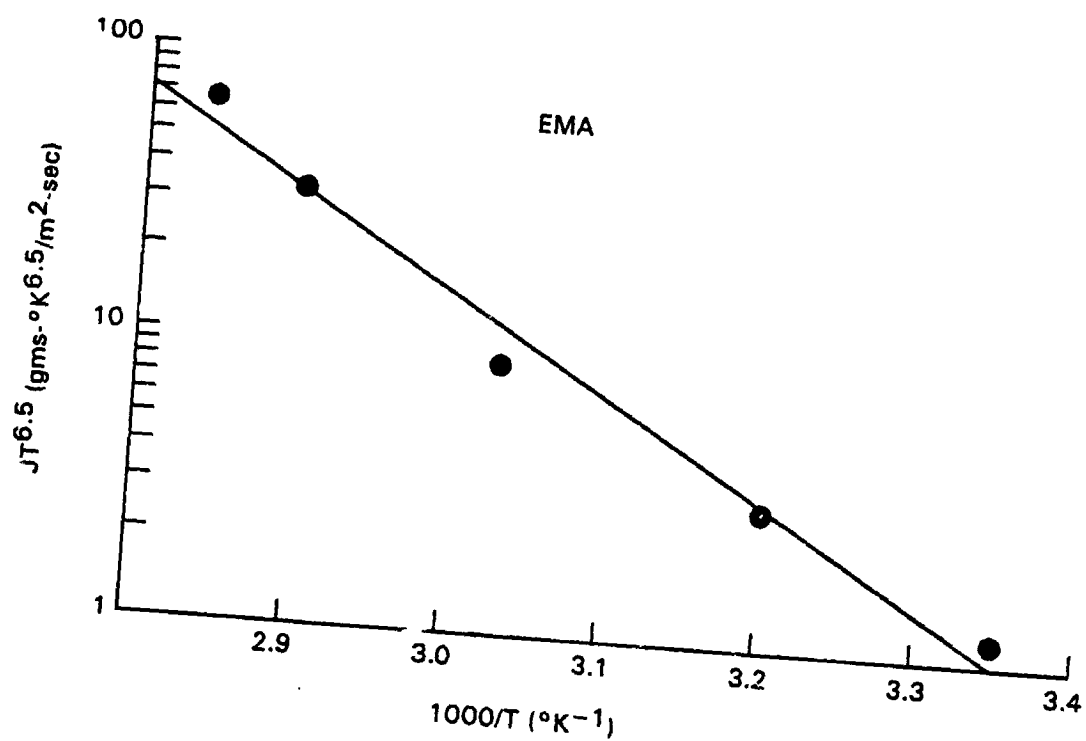
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RELIABILITY PHYSICS



RELIABILITY PHYSICS

Results

	Activation Energy (Kcal./mole)		Solubility Parameter
	<u>Q_p</u>	<u>Q_J</u>	<u>S</u>
Tedlar	~ 2.9	15	.614
EMA	~ 3.1	15	5.2
PVB	~ 1.4	15	175
EVA	~ 2.8	18	730
Theoretical	4.6	14.4	—

Results

	Permeability $P \times 10^9$ (gms/m-sec-mmHg)	Thickness $d \times 10^6$ (m)	Resistance $R \times 10^5$ (m ² -sec-mmHg/gm)
Tedlar	0.2	63	3.1
EMA	2.0	480	2.4
EVA	4.0	470	1.2
PVB	8.0	803	1.0

Results

Composites at 25°C

Permeability $P \times 10^9$
(gms/m-sec-mmHg)

	<u>Experimental</u>	<u>Calculated</u>
PVB/T	1.6	1.5
EMA/T	2.0	1.0
EVA/T	1.1	0.8

Conclusions

- $P_T < P_{EMA} < P_{EVA} < P_{PVB}$
- Temperature dependence of J and P for PVB, EMA, and T is consistent with evaporation-self diffusion-condensation model
- P of PVB/T composite is consistent with discrete interface model
- Water solubility: greatest in PVB, least in Tedlar

SILICON MATERIALS

Ralph Lutwack, Chairman

The session on Silicon Materials consisted of two presentations.

JPL reviewed the FSA-sponsored Workshop on Low-Cost Polysilicon for Terrestrial Photovoltaic Solar Cell Applications which was held in Las Vegas, Nevada, October 28-30, 1985.

Union Carbide Corp. (UCC) reported on their development of fluidized-bed reactor technology for producing silicon by the pyrolysis of silane. The technical effort on this program was completed.